Docket Number: 081468-0306588

Client Reference: P-0367.010-US

PATENT APPLICATION
NOV 1 9 2003

IN THE UNITED STATES PATERS AND TRADEMARK OFFICE

In Re the Application of

MIRCEA DUSA, et al.

Group Art Unit: (Unknown)

Application No.: 10/696,726

Examiner: (Unknown)

Filed: October 30, 2003

Confirmation No.: (Unknown)

For: TEST PATTERN, INSPECTION METHOD, AND DEVICE MANUFACTURING

METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR 1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449's. One copy of the non-U.S. Patent/Application reference is attached, together with a copy of each of the literature references. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed before the mailing date of the first Office Action on the merits in the present application. No certification or fee is required.

The Patent/Application references were cited in a counterpart foreign application. The European Search Report is in the English language and is attached for the Examiner's information.

Respectfully Submitted,

Kerry T. Hartman

Registration Number 41818

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PTO/SB/08a (05-03)
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Subs	stitute for form 1449A/PTO		Complete if Known			
-			Application Number	10/696,726		
IN	FORMATION DISC	CLOSURE	Filing Date	10/30/2003		
	TATEMENT BY AF		First Named Inventor	MIRCEA DUSA		
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Sheet	1	of 1	Attorney Docket Number	081468-0306588		

					U. S. PATENT I	DOCUMENTS	
Examiner Initials*	Cite No. ¹	Documer Number-Kind	nt Number d Code ^{2 (lf kn)}		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	1		041373		April 11, 2002	LITTAU ET AL.	See Search Report
	2		072003		June 13, 2002	BRILL ET AL.	See Search Report
	3	^{US-} 6,458,6	505	B1	October 1, 2002	STIRTON	See Search Report
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Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (<i>if known</i>)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	י
	4	WO 02/065545	A2	August 22, 2002	SEZGINER et al.	See Search Report	
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Signature	Considered	1

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This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.



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Substitute for	r form 1449B/PTO			Complete if Known		
				Application Number	10/696,726	
	RMATION DIS			Filing Date	10/30/2003	
STAT	EMENT BY	APPL	ICANT	First Named Inventor	MIRCEA DUSA	
				Art Unit		
	(Use as many sheets as	necessary)	Examiner Name	(Unknown)	
Sheet	1	of	1	Attorney Docket Number	081468-0306588	

·	NON PATENT LITERATURE DOCUMENTS	
Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
5	NIU ET AL., "Specular Spectroscopic Scatterometry in DUV Lithography," SPIE, SPIE Conference on Metrology, Inspection, and Process Control for Microlithography XIII (Santa Clara, CA), p. 159-168, vol. 3677 (March 1999).	-
6	RAYMOND ET AL., "Multiparameter Grating Metrology Using Optical Scatterometry," J. Vac. Sci. Technol. B, American Institute of Physics, Vol. 15 (No. 2), p. 361-368, (Mar/Apr 1997).	
	No. ¹	Cite No.1 Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. NIU ET AL., "Specular Spectroscopic Scatterometry in DUV Lithography," SPIE, SPIE Conference on Metrology, Inspection, and Process Control for Microlithography XIII (Santa Clara, CA), p. 159-168, vol. 3677 (March 1999). RAYMOND ET AL., "Multiparameter Grating Metrology Using Optical Scatterometry," J. Vac.

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Signature	Considered	

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